

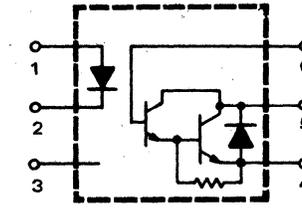


SOLID STATE OPTO ELECTRONICS

Photon Coupled Isolator H11G1-H11G2

Ga As Infrared Emitting Diode & NPN Silicon Darlington Connected Phototransistor

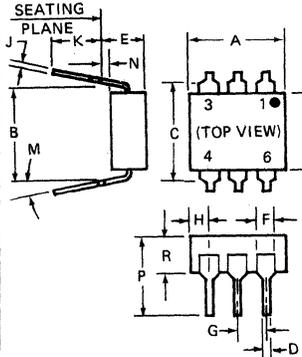
The General Electric H11G series consists of a gallium arsenide, infrared emitting diode coupled with a silicon, darlington connected, phototransistor which has an integral base-emitter resistor to optimize switching speeds and elevated temperature characteristics.



absolute maximum ratings: (25°C)

INFRARED EMITTING DIODE		
Power Dissipation	*100	milliwatts
Forward Current (Continuous)	60	milliamps
Forward Current (Peak)		
(Pulse width 300 μsec, 2% Duty Cycle)	0.5	amperes
(Pulse width 1 μsec, 300 Hz)	3	amperes
Reverse Voltage	6	volts
*Derate 1.33mW/°C above 25°C ambient.		

DARLINGTON CONNECTED PHOTO-TRANSISTOR		
Power Dissipation	**150	milliwatts
V _{CEO}		
— H11G1	100	volts
— H11G2	80	volts
V _{CBO}		
— H11G1	100	volts
— H11G2	80	volts
V _{EBO}	7	volts
Collector Current (Continuous)		
— Forward	150	milliamps
Collector Current (Continuous)		
— Reverse	10	milliamps
**Derate 2.0mW/°C above 25°C ambient.		



SYMBOL	MILLIMETERS		INCHES		NOTES
	MIN.	MAX.	MIN.	MAX.	
A	8.38	8.89	.330	.350	
B	7.62 REF.		.300 REF.		1
C	—	8.64	—	.340	2
D	.406	.508	.016	.020	
E	—	5.08	—	.200	3
F	1.01	1.78	.040	.070	
G	2.28	2.80	.090	.110	
H	—	2.16	—	.085	4
J	.203	.305	.008	.012	
K	2.54	—	.100	—	
M	—	15°	—	15°	
N	.381	—	.015	—	
P	—	9.53	—	.375	
R	2.92	3.43	.115	.135	
S	6.10	6.86	.240	.270	

- NOTES:
 1. INSTALLED POSITION LEAD CENTERS.
 2. OVERALL INSTALLED DIMENSION.
 3. THESE MEASUREMENTS ARE MADE FROM THE SEATING PLANE.
 4. FOUR PLACES.

TOTAL DEVICE
Storage Temperature -55°C to +150°C
Operating Temperature -55°C to +100°C
Lead Soldering Time (at 260°C) 10 seconds
Surge Isolation Voltage (Input to Output)
3535 V _(peak) 2500 V _(RMS)
Steady-State Isolation Voltage (Input to Output)
2125 V _(peak) 1500 V _(RMS)

individual electrical characteristics:(25°C)

EMITTER	TYP.	MAX.	UNITS
Forward Voltage (I _F = 10mA)	1.1	1.5	volts
Reverse Current (V _R = 3V)	—	10	microamps
Capacitance (V = 0, f = 1 MHz)	50	—	picofarads

DETECTOR	MIN.	TYP.	MAX.	UNITS
Breakdown Voltage — V _{(BR)CEO} (I _C = 1.0mA, I _F = 0) — H11G1	100	—	—	volts
— H11G2	80	—	—	volts
Breakdown Voltage — V _{(BR)CBO} (I _C = 100μA, I _F = 0) — H11G1	100	—	—	volts
— H11G2	80	—	—	volts
Breakdown Voltage — V _{(BR)EBO} (I _E = 100μA, I _F = 0)	7	—	—	volts
Collector Dark Current — I _{CEO} (V _{CE} = 80V, I _F = 0) — H11G1	—	—	100	nanoamps
(V _{CE} = 60V, I _F = 0) — H11G2	—	—	100	nanoamps
(V _{CE} = 80V, I _F = 0, T _A = 80°C)	—	—	100	microamps
— H11G1	—	—	100	microamps
(V _{CE} = 60V, I _F = 0, T _A = 80°C)	—	—	100	microamps
— H11G2	—	—	100	microamps
Capacitance (V _{CE} = 10V, f = 1 MHz)	—	6	—	picofarads

Covered under U.L. component recognition program, reference file E51868

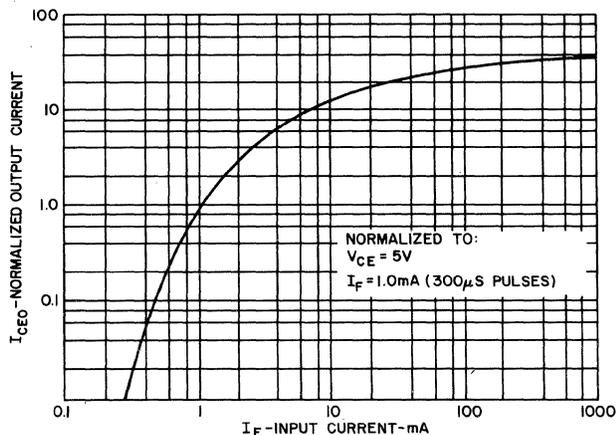
VDE Approved to 0883/6.80 0110b Certificate # 35025

coupled electrical characteristics:(25°C)

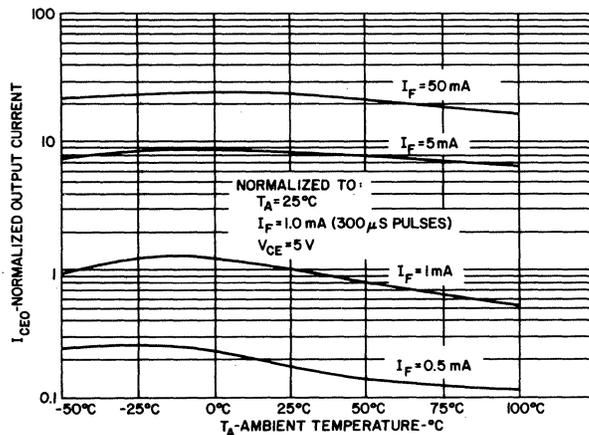
H11G1, H11G2

	MIN.	TYP.	MAX.	UNITS
DC Current Transfer Ratio – ($I_F = 10\text{ mA}$, $V_{CE} = 1\text{ V}$)	1000	–	–	%
– ($I_F = 1\text{ mA}$, $V_{CE} = 5\text{ V}$)	500	–	–	%
Saturation Voltage – Collector to Emitter – ($I_F = 1\text{ mA}$, $I_C = 1\text{ mA}$)	–	0.75	1.0	volts
– ($I_F = 16\text{ mA}$, $I_C = 50\text{ mA}$)	–	0.85	1.0	volts
Isolation Resistance (Input to Output Voltage = 500 V _{DC})	100	–	–	gigohms
Input to Output Capacitance (Input to Output Voltage = 0, f = 1 MHz)	–	–	2	picofarads
Switching Speeds:				
On-Time – ($V_{CE} = 5\text{ V}$, $R_L = 100\Omega$, $I_F = 10\text{ mA}$)	–	5	–	microseconds
Off-Time – (Pulse width $\leq 300\ \mu\text{sec}$, $f \leq 30\text{ Hz}$)	–	100	–	microseconds

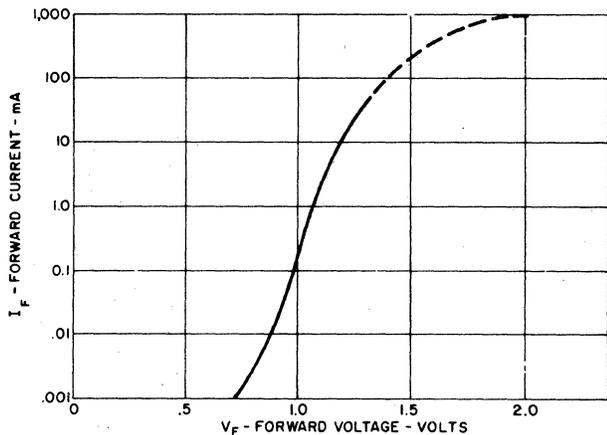
TYPICAL CHARACTERISTICS



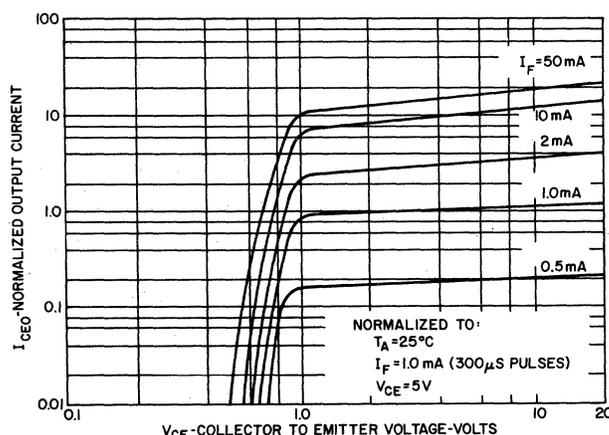
OUTPUT VS. INPUT CURRENT



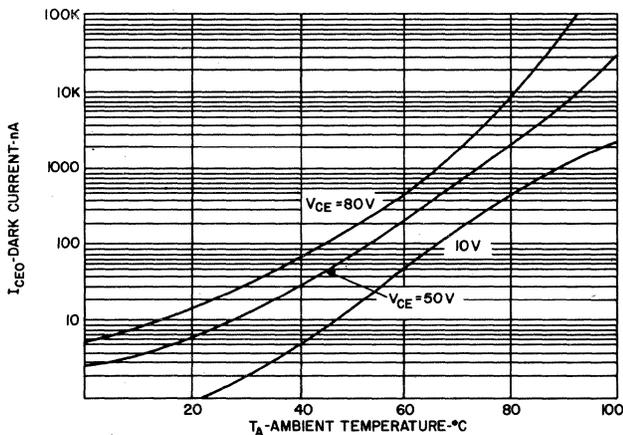
OUTPUT VS. TEMPERATURE



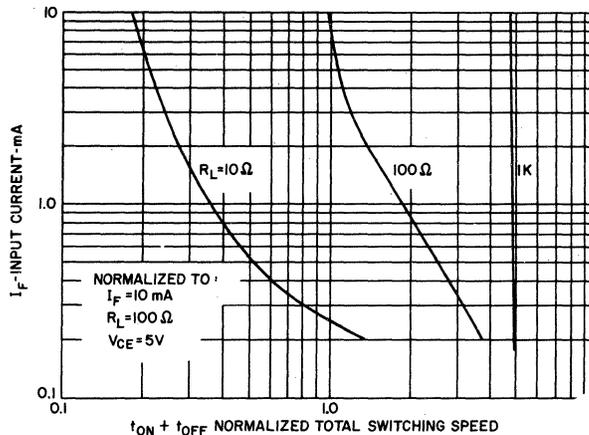
INPUT CHARACTERISTICS



OUTPUT CHARACTERISTICS



DARK CURRENT



SWITCHING SPEED